Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/602,146	LEE ET AL.
Examiner	Art Unit
lordany Núñoz	2170

SEARCHED				
Class	Subclass	Date	Examiner	
715	806	12/22/2006	ИС	
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INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East: USPAT, US PGPUB, EPO, JPO, Derwent, IBM-IDB	12/22/2006	JN		
NPL ·	12/22/2006	JN		
Consulted with primary examiner, Ba Huynh, AU 2179	12/22/2008	ŊŲ		
Seouth updated	5/3007	ΛN		
Seouh updated	1/15/07	10		
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